



Minutes

Fifteenth Meeting of Electromechanical Components and Mechanical Structures for Electronic Equipment's Sectional Committee LITD 03

(Virtual Webex Meeting), 13th June 2024 (Thursday); Time: 1100h,

In the Chair: Shri Anand Laddha, BARC

Member Secretary: Ms. Alismita Khag

Sr. No.	Name of Member	Organization
1	Shri Sanjiv singh	Gilard
2	Lt. Col AP Verma	DGQA
3	Shri Bholanath Sonkar	DGQA
4	Dr. G.S. Darbari	Darbari Industries
5	Mr. MP Dubey	Electronic Industries Association of India
6	Shri V. Venkappa	Elico
7	Mr. Eugene George K	TE Connectivity
8	Mr. Niranjn Hegde K	TE Connectivity
9	Mr. Prithviraj B Mane	Elcom International Private Limited
10	Mr. P. Rajanikanth	NTH
11	Mr. Sandeep Singh Chauhan	NTH
12	Mr. S.V. Sharma	MSME Testing Center

ITEM 0 WELCOME AND OPENING REMARKS

The member secretary welcomed the chairperson and the members present in the meeting. The meeting started with a round of introduction.

ITEM 1 CONFIRMATION OF THE MINUTES OF PREVIOUS MEETING

The minutes of the 14th meeting of Electromechanical Components and Mechanical Structures for Electronic Equipment's Sectional Committee LITD 03 held on 11-12-2023, virtually, was formally confirmed by the Committee.

ITEM 2 COMPOSITION OF SECTIONAL COMMITTEE

2.1 The committee noted the information given at Item 2.1 of the agenda and decided to write to the following organizations for ascertaining continued participation in the committee:

- OEN India - Mr. Biju K Paul (Principal Member), Mr. Ratheesh Kumar P (Alternate Member)
Mr. Lilu Jacob (Alternate Member)

Shri M P Dubey, ELCINA was requested to follow up with the representatives of OEN India Ltd.

ITEM 3 REVIEW OF PUBLISHED INDIAN STANDARDS

3.1 The Committee noted the information given at Item 3.1 of the Agenda and approved the following draft standards for finalization:



SI No.	Doc No.	Title
1.	LITD/03/23483 (Identical To: IEC 60512-4-1 : 2003)	Connectors for electronic equipment - Part - 4 Tests and measurements - Section - 1: Voltage stress tests - Test 4a: Voltage proof
2.	LITD/03/23486 (Identical To: IEC 60512-4-2 : 2002)	Connectors for electronic equipment Part -4 Tests and measurements Section - 2: Voltage stress tests - Test 4b: Partial discharge
3.	LITD/03/23487 (Identical To: IEC 60512-4-3 : 2002)	Connectors for electronic equipment Part - 4 Tests and measurements Section - 3: Voltage stress tests - Test 4c: Voltage proof of pre-insulated crimp barrels
4.	LITD/03/23495 (Identical To: IEC 60512-2-1: 2002)	Connectors for electronic equipment Part 2 Tests and measurements Section 1: Electrical continuity and contact resistance tests Test 2a: Contact resistance Millivolt level method
5.	LITD/03/23496 (Identical To: IEC 60512-2-2:2003)	Connectors for electronic equipment Part 2 Tests and measurements Section 2: Electrical continuity and contact resistance tests Test 2b: Contact resistance Specified test current method
6.	LITD/03/23497 (Identical To: IEC 60512-2-3:2002)	Connectors for electronic equipment Part 2 Tests and measurements Section 3: Electrical continuity and contact resistance tests Test 2c: Contact resistance variation
7.	LITD/03/23498 (Identical To: IEC 60512-2-5: 2003)	Connectors for electronic equipment Part 2 Tests and measurements Section -5: Electrical continuity and contact resistance tests Test 2e: Contact disturbance
8.	LITD/03/23499 (Identical To: IEC 60512-2-6: 2002)	Connectors for electronic equipment Part 2 Tests and measurements Section 6: Electrical continuity and contact resistance tests Test 2f: Housing shell electrical continuity
9.	LITD/03/23500 (Identical To: IEC 60512-3-1: 2002)	Connectors for electronic equipment Part 3 Tests and measurements Section 1: Insulation tests Test 3a: Insulation resistance

ITEM 4 REVIEW OF PRE 2000 STANDARDS

4.1 The committee noted the information given at item 4.1 of the agenda and after detailed deliberations the following were decided:



Sl. No	IS No.	Title	Base Standard	Latest Status	Decision
1.	IS 12448 (Part 2/Sec 1) : 1988	Basic testing procedures and measuring methods for electrotechnical components for electronic equipment: Part 2 general examination, electrical continuity and contact resistance tests, insulation tests and voltage stress tests: Sec 1 general examination	IEC 60512 - 2 : 1985	IEC 60512-1-1:2002 is the revised version of the base standard	IS 12448 (Part 2/Sec 1) : 1988 to be withdrawn.
2.	IS 12448 (Part 5/Sec 1) : 1989	Basic testing procedures and measuring methods for electromechanical components for electronic equipment: Part 5 impact tests (Free Components), static load tests (Fixed Components), endurance tests and overload tests: Sec 1 impact tests (Free Components)	IEC 60512-5 : 1977	IEC 60512-5-1:2002 is the revised version of the base standard	IS 12448 (Part 5/Sec 1): 1989.
3.	IS 12448 (Part 5/Sec 2) : 1989	Basic testing procedure and measuring methods for electromechanical components: Part 5 (Fixed For Electronic Equipment) Impact Tests (Free Components), static load tests components), endurance tests and overload tests . Sec 2 static load tests (Fixed Components)	IEC 60512-5 : 1977	IEC 60512-5-1:2002 is the revised version of the base standard	IS 12448 (Part 5/Sec 2) : 1989 to be withdrawn & IEC 60512-5-1:2002 to be adopted as an Indian Standard.
4.	IS 12448 (Part 5/Sec 3) : 1989	Basic testing measuring standard procedures and methods for electromechanical components for electronic equipment: Part 5 impact tests (Free Components), static load tests (Fixed Components), endurance tests and overload tests: Sec 3 endurance tests	IEC 60512-5 : 1977	IEC 60512-5-1:2002 is the revised version of the base standard	IS 12448 (Part 5/Sec 3): 1989 to be withdrawn & IEC 60512-5-1:2002 to be adopted as an Indian Standard



5.	IS 12448 (Part 5/Sec 4) : 1989	Basic testing procedures and measuring methods for electromechanical components for electronic equipment: Part 5 impact tests (Free Components), static load tests (Fixed Components), endurance tests and overload tests: Sec 4 overload tests	IEC 60512-5 : 1977	IEC 60512-5-1:2002 is the revised version of the base standard	IS 12448 (Part 5/Sec 4) : 1989 to be withdrawn & IEC 60512-5-1:2002 to be adopted as an Indian Standard.
6.	IS 12448 (Part 9) : 1992	Basic testing procedures and measuring methods for electromechanical components for electronic equipment: Part 9 Cable-clamping tests, explosion hazard tests, chemical resistance tests, fire hazard tests of	IEC 60512-9 : 1977	IEC 60512-9-1:2010 is the revised version of the base standard	IS 12448 (Part 9) : 1992 to be withdrawn & IEC 60512-9-1:2010 to be adopted as an Indian Standard

ITEM 5 DATE AND PLACE FOR THE NEXT MEETING

- 5.1** The committee decided to host the next meeting in Sep 2024 in hybrid mode. The date & place for the meeting would be decided in consultation with the Chair.

ITEM 6 ANY OTHER BUSINESS

- 6.1** The committee deliberated on the draft on ‘Standard for general requirement for connectors in electronic Appliances’ provided by Shri V. Venkappa, Elico Industries and was of the view that IS/IEC 60512-1 already exists, which specifies the general requirement for different types of connector. However it was felt that a standard road map on connector can be formulated in the form of a white paper by the committee.
- 6.2** Shri V. Venkappa was requested to formulate the draft white paper and submit the same before the next meeting. Other members of the committee were requested to assist Shri V. Venkappa to formulate this document.
- 6.2** As there was no other business, the meeting ended with a vote of thanks to the Chair and the members.